

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET
MI22-1422SERIAL NO.
UnknownLIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Scott E. Moore et al.FILING DATE
Filed HerewithGROUP
Unknown

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WB	AA	5,755,614	05/26/98	Adams et al.			
WB	AB	5,664,990	09/09/97	Adams et al.			
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AF							
	AG							
	AH							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

WB	AI		http://www.intratechnology.com/html/sensors.htm , Intra Technology, <i>Sensors</i> , 03/25/99, 2 pages
WB	AJ		http://www.ftsync.com/complete/analite/analite.htm , FTS, <i>Analite-SDI Turbidity Sensor</i> , 03/25/99, 1 page
WB	AK		http://www.customsensors.com/optimax.htm , Custom Sensors & Technology, <i>OptiMax 6000 Series Process Photometric Analyzers</i> , 03/25/99, 2 pages
WB	AL		http://www.reflectronics.com/reflectronics_inc_contents.htm , Reflectronics, Inc., <i>Fiber Optic Backscatter Sensor</i> , 03/25/99, 1 page
WB	AM		http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st , Gary O'Brien, Honeywell, <i>Turbidity Sensor for Electromechanical Dishwasher Control</i> , 1998-1999, 11 pages
WB	AT		http://www.impomag.com/O_automa/10970064.htm , ABB Instrumentation, <i>The Stockroom, Photodiode Sensor</i> , 1999, 1 page

EXAMINER

Willie Berry, Jr.

DATE CONSIDERED

1/23/02

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

#2

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1422	SERIAL NO. 09/556,491
LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Scott E. Moore et al.	
				FILING DATE April 21, 2000	
				GROUP Unknown	

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
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FOREIGN PATENT DOCUMENTS

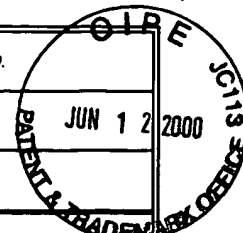
Document Number	Date	Country	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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	AI	
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EXAMINER <div style="font-family: cursive; font-size: 1.2em;">Willie Berry, Jr.</div>	DATE CONSIDERED <div style="font-family: cursive; font-size: 1.2em;">1/23/02</div>
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Form PTO-1449

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1422SERIAL NO.
09/556,491

LIST OF ART CITED BY APPLICANT

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APPLICANT
Scott E. Moore et al.FILING DATE
April 21, 2000GROUP
Unknown

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WB	AA	5,836,805	11/1998	Obeng			
WB	AB	6,066,030	5/2000	Uzoh			
WB	AC	6,077,147	6/2000	Yang et al.			
WB	AD	6,048,256	4/2000	Obeng et al.			
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		Document Number	Date	Country	Class	Subclass	Translation	
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EXAMINER

Willie Berry, Jr.

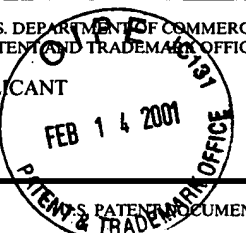
DATE CONSIDERED

1/23/02

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1422	SERIAL NO. 09/556,491
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.	
				FILING DATE April 21, 2000	GROUP 3723



*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
BT WB	AA	5,653,624	8/5/97	Ishikawa et al.		
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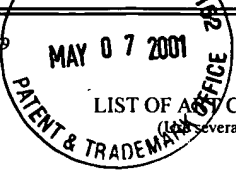
FOREIGN PATENT DOCUMENTS							
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Form PTO-1449					U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1422		SERIAL NO. 09/556,491	
LIST OF ARTS CITED BY APPLICANT (List several sheets if necessary)							APPLICANT Scott E. Moore et al.			
							FILING DATE April 21, 2000		GROUP 3723	
U.S. PATENT DOCUMENTS										
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate				
WB	AA	5,718,620	2/17/98	Tanaka et al.						
WB	AB	5,885,134	3/23/99	Shibata						
WB	AC	6,099,386	8/8/00	Tsai et al.						
WB	AD	6,159,082	12/12/00	Sugiyama et al.						
WB	AE	6,165,048	12/26/00	Russ et al.						
WB	AF	6,183,352 B1	2/6/01	Kurisawa						
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Willie Berry Jr.			1/23/02							
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